



Substitute for form 1449A/PTO				Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				Application Number	10/079,512
				Filing Date	February 22, 2002
				First Named Inventor	Shunpei YAMAZAKI
				Art Unit	2826
				Examiner Name	Remmon R. Forde
Sheet	2	of	2	Attorney Docket Number	740756-2441

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document		Publication Date MM-DD-YYYY	Name of Patentee or Application of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Country Code ²	Number ³ Kind Code ⁴ (if known)			
A.S.		JP	04-258160	09-14-1992	Miyake	Abstract
A.S.		JP	04-369271	12-22-1992	Takeda et al.	Full
A.S.		JP	05-102483	04-23-1993	Ueda	Full
		JP	06-148685	05-27-1994	Nakazono et al.	Full
A.S.		JP	07-130652	05-19-1995	Ohtani et al.	Abstract
		JP	07-235680	09-05-1995	Goto et al.	Full
		JP	08-078329	03-22-1996	Ohtani	Abstract
		JP	08-264784	10-11-1996	Kurokawa	Abstract
		JP	08-274336	10-18-1996	Uemoto et al.	Full
		JP	09-191111	07-22-1997	Zhang	Abstract
		JP	09-293600	11-11-1997	Nakagawa et al.	Abstract
		JP	10-104659	04-24-1998	Nakajima et al.	Abstract
		JP	10-135468	05-22-1998	Yamazaki et al.	Abstract
		JP	10-135469	05-22-1998	Yamazaki et al.	Abstract
		JP	10-233511	09-02-1998	Seto	Full
		JP	10-294280	11-04-1998	Yamazaki et al.	Abstract
		JP	11-191628	07-13-1999	Yamazaki et al.	Abstract
		JP	11-345767	12-14-1999	Yamazaki et al.	Abstract
		JP	11-354442	12-24-1999	Ohtani et al.	Abstract
A.S.		JP	60-127761	07-08-1985	Fuse	Abstract

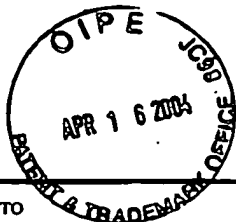
OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	1 ²
A.S.		HATANO ET AL., "A NOVEL SELF ALIGNED GATE-OVERLAPPED LDD POLY-SI TFT WITH HIGH RELIABILITY AND PERFORMANCE", IEDM 1997, PP. 523-526	/
A.S.		SHIMOKAWA ET AL., "CHARACTERIZATION OF HIGH-EFFICIENCY CAST-SI SOLAR CELL WAFERS BY MBIC MEASUREMENT", JAPANESE JOURNAL OF APPLIED PHYSICS, VOL. 27, NO. 5, MAY 1988, PP. 751-758	/

Examiner Signature	<i>[Signature]</i>	Date Considered	12/3/04
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U.S. PATENT DOCUMENTS					
Examiner Initials [*]	Cite No. ¹	U.S. Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number - Kind Code ² (if known)			
		US-			
		US-			
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Examiner Initials [*]	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ³
		Country Code ⁴ Number ⁵ Kind Code ² (if known)				
A-Z		JP-06-148685	05/27/1994	NAKAZONO et al.		Full
A-Z		JP-08-264784	10/11/1996	KUROKAWA		Partial

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials [*]	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ³
A-Z		U.S. Patent Application Serial No. 09/433,705; Filed: November 4, 1999; Shunpei Yamazaki; "Method of Fabricating a Semiconductor Device" (Specification; Claims, Abstract, Drawings, Official Filing Receipt and Official Action dated 3/12/04 with Partial English Translation of Japanese Patent No. 8-264784)); Status: Pending	

Examiner Signature		Date Considered	12/3/04
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